Applicant(s)/Patent Under Reexamination 10/656,153 OGAWA ET AL. Notice of References Cited Art Unit Examiner

Application/Control No.

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,218,232	04-2001	Heo, Yeon Cheol	438/238
*	В	US-2001/0017385	08-2001	Yamamoto, Ichiro	257/306
*	С	US-6,404,414	06-2002	Ishii, Kenya	345/90
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ī	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.